

<b>Notice of References Cited</b>	Application/Control No. 10/526,870	Applicant(s)/Patent Under Reexamination KEVENAAR ET AL.	
	Examiner Bao-Quan T. Ho	Art Unit 2629	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,712,652	01-1998	Sato et al.	345/90
*	B	US-6,529,209	03-2003	Dunn et al.	345/629
*	C	US-6,980,177	12-2005	Struyk, David A	345/8
*	D	US-7,319,755	01-2008	Struyk, David A	380/213
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 09083512 A	03-1997	Japan	HIGURE M et al.	X
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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